

Search Notes

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10/617,172

Examiner

Tianjie Chen

Applicant(s)/Patent under
Reexamination

KIM ET AL.

Art Unit

2656

SEARCHED

Class	Subclass	Date	Examiner
Updated		2/2/2006	TJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR